

PATENT
56318-025 5231

Express Mail Label No.: EL 669 015 669 US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:
MATSUNAGA, et al.

Serial No.: Not Assigned

Filed: December 8, 2000

For: PROBE PIN FOR TESTING ELECTRICAL
CHARACTERISTICS OF APPARATUS, PROBE CARD
USING THE PROBE PINS, AND METHOD FOR
FABRICATING THE PROBE PIN

Group No.: Not Assigned

Examiner: Not Assigned

Assistant Commissioner For Patents
Washington, D.C. 20231

TRANSMITTAL OF PRIORITY DOCUMENT

Dear Sir:

Enclosed herewith is a certified copy of Japanese patent application No. 11-363317 which was filed December 21, 1999, from which priority is claimed under 35 U.S.C. §119 and Rule 55.

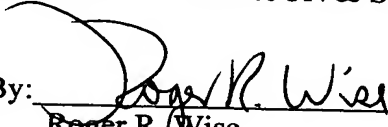
Acknowledgment of the priority document(s) is respectfully requested to ensure that the subject information appears on the printed patent.

Respectfully submitted,

PILLSBURY MADISON & SUTRO LLP

Dated: December 8, 2000

By:


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日本国特許庁
PATENT OFFICE
JAPANESE GOVERNMENT

別紙添付の書類に記載されている事項は下記の出願書類に記載されている事項と同一であることを証明する。

This is to certify that the annexed is a true copy of the following application as filed with this Office.

出願年月日

Date of Application:

1999年12月21日

出願番号

Application Number:

平成11年特許願第363317号

願人

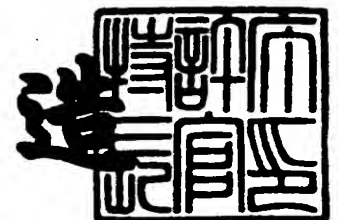
Applicant(s):

株式会社東芝

2000年10月27日

特許庁長官
Commissioner,
Patent Office

及川耕造



出証番号 出証特2000-3089481

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